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Examiner

Applicant(s)/Patent under Reexamination

MIAO ET AL. Art Unit

1633

Michael D. Burkhart

1	SEARCHED					
	Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
Updated inventor name and STIC SEQ ID NOs 1,4,7, 9 searches		10/16/07	MB			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
Updated inventor name search (EAST), see search printout.	10/19/2007	мв			
Updated USPat, USPgPub,EPO,JPO, Derwent keyword search (EAST), see search printout.	↓				
Allowance conference: J. Woitach	10/17/2007				
STIC search of SEQ ID NOs: 1-6, 9, 10.	10/31/2005				
STIC search of SEQ ID NOs: 7, 8.	4/18/06	Ţ			

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